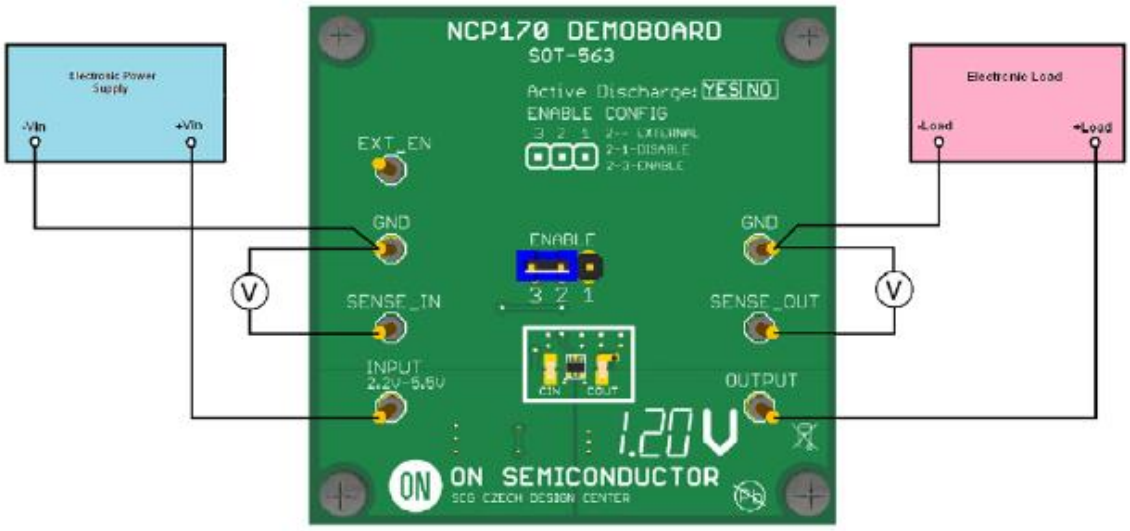
ON Semiconductor®

Test Procedure for the NCP170AXV330GEVB Evaluation Board



Test procedure:

1.Check the position of jumper and correct this if necesary in acordance with the picture above.
2. Connect the test setup as shown Figure above
3. Appy an input voltage **Vin = 4.3 V**
4. Appy Iout = 0mA load.
5. Check that Vout is **3.3 V +/-1%**.
6. Increase Iout up to **0.15 A**
7. Check that Vout is **3.3 V +/-1%**.
7. Increase Vin up to **5.5 V** and decrease the load in accordance with **SOA**
8. Power down the Load
9. Power down the Vcc
10. End of test